



Standard Guide to Charge Control and Charge Referencing Techniques in X-Ray Photoelectron Spectroscopy¹

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1. Scope

1.1 This guide acquaints the XPS user with the various charge control and charge shift referencing techniques that are and have been used in the acquisition and interpretation of X-ray photoelectron spectroscopy (XPS) data from surfaces of insulating specimens.

1.2 This guide is intended to apply to charge control and charge referencing techniques in XPS and is not necessarily applicable to electron-excited systems.

1.3 SI units are standard unless otherwise noted.

1.4 *This standard does not purport to address all of the safety problems, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.*

2. Referenced Documents

2.1 ASTM Standards:

E 673 Terminology Relating to Surface Analysis²

E 902 Practice for Checking the Operating Characteristics of X-Ray Photoelectron Spectrometers²

E 1078 Guide for Specimen Handling in Auger Electron Spectroscopy, X-Ray Photoelectron Spectroscopy, and Secondary Ion Mass Spectrometry²

E 1829 Guide for Specimen Preparation and Mounting in Surface Analysis²

3. Terminology

3.1 Definitions:

3.1.1 See Terminology E 673 for definitions of terms used in X-ray photoelectron spectroscopy.

4. Overview of Charging Effects

4.1 For insulating specimen surfaces, the emission of photoelectrons following X-ray excitation may result in a buildup of a positive surface charge. This positive surface charge changes the surface potential thereby shifting the measured energies of the photoelectron peaks to higher binding energy.

This binding energy shift may reach a nearly steady-state value of between 2 and 5 eV for spectrometers equipped with nonmonochromatic X-ray sources. The surface potential charge and the resulting binding energy shift is, generally, larger for spectrometers equipped with monochromatic X-ray sources because of the, generally, lower flux of low-energy electrons impinging on the specimen surface. This lower flux arises because focused, monochromatic X-ray beams irradiate only a portion of the specimen and not other nearby surfaces (for example, the specimen holder) that are sources of low-energy electrons. The absence of an X-ray window in many monochromatic X-ray sources (or a greater distance of the specimen from the X-ray window) also eliminates another source of low-energy electrons.

4.2 The amount of induced surface charge, its distribution across the specimen surface, and its dependence on experimental conditions are determined by several factors including specimen composition, homogeneity, magnitude of surface conductivity, total photoionization cross-section, surface topography, and availability of neutralizing electrons. The presence of particles on or different phases in the specimen surface may result in an uneven distribution of charge across the surface, a phenomenon known as differential charging. Some specimens undergo time-dependent changes in the level of charging because of electron, X-ray, or thermal damage or because of volatilization. Such specimens may never achieve steady-state potentials.

4.3 Several techniques have been developed for the purpose of controlling charge buildup and the subsequent changes in surface potential in order to obtain meaningful and reproducible data from insulating specimens. These techniques are employed during the data acquisition and are discussed in 7.1.

4.4 Several techniques have been developed for the purpose of correcting the binding energy shifts that result from surface charging. These corrections are performed after the data has been accumulated and are discussed in 7.2.

4.5 The use of the various charge control or charge referencing techniques described in this guide may depend on the available instrument as well as the specimen being analyzed.

5. Significance and Use

5.1 The acquisition of chemical information from variations in the energy position of peaks in the XPS spectrum is of primary interest in the use of XPS as a surface analytical tool.

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² *Annual Book of ASTM Standards*, Vol 03.06.

Surface charging acts to shift spectral peaks independent of their chemical relationship to other elements on the same surface. The desire to eliminate the influence of surface charging on the peak positions and peak shapes has resulted in the development of several empirical methods designed to assist in the interpretation of the XPS peak positions, determine surface chemistry, and allow comparison of spectra of conducting and nonconducting systems of the same element. It is assumed that the spectrometer is generally working properly for non-insulating specimens (see Practice E 902).

5.2 No ideal method has been developed to deal with surface charging. For insulators, an appropriate choice of any control or referencing system will depend on the nature of the specimen, the instruments, and the information needed. The appropriate use of charge control and referencing techniques will result in more consistent, reproducible data. Researchers are strongly urged to report both the control and referencing techniques that have been used, the specific peaks and binding energies used as standards (if any), and the criteria applied in determining optimum results so that the appropriate comparisons may be made.

6. Apparatus

6.1 One or more of the charge compensation techniques mentioned in this guide may be employed in virtually any XPS spectrometer.

6.2 Some of the techniques outlined require special accessory apparatus, such as electron flood sources or a source for evaporative deposition.

6.3 Certain specimen mounting procedures, such as mounting the specimen under a fine metal mesh **(1)**³, can enhance electrical contact of the specimen with the specimen holder, or reduce the amount of surface charge buildup. This and other methods of specimen mounting to reduce static charge are described in detail in Guide E 1078 and Guide E 1829 .

7. Procedures

7.1 The methods described here involve charge control (the effort to control the buildup of charge at a surface or to minimize its effect), charge referencing (the effort to determine a reliable binding energy despite buildup of charge), or some combination of the two. For charge control, peak shape is the most important parameter to consider. Correcting the peak position is accomplished separately using an appropriate charge referencing technique. In some circumstances the Auger parameter can provide chemical information without the need to resort to surface potential corrections.

7.1.1 *Methods to Control Surface Potential:*

7.1.1.1 *Electron Flood Gun (2-5)*—Use low-energy electron flood guns to stabilize the static charging of insulators examined by XPS **(3)**, in particular when monochromatized X-rays are employed. Optimum operating conditions, for example, filament position, electron energy, and electron current, depend upon the orientation of the electron flood gun with respect to the specimen and upon the particular design of the electron

flood gun and must, in general, be determined by the user. Use low-electron energies (usually 10 eV or less) to maximize the neutralization effect and reduce the number of electron bombardment-induced reactions. A metal screen placed on or above the specimen can help **(6,7)**.

7.1.1.2 *Ultraviolet Flood Lamp (8)*—Ultraviolet radiation can also produce low-energy electrons (for example, from the specimen holder) that may be useful in neutralizing specimen charging.

7.1.1.3 *Specimen Heating*—For a limited number of specimens, heating can increase the electrical conductivity of the specimen, thus decreasing charging.

7.1.1.4 *Specimen Biasing*—Applying a low-voltage bias (−10 to + 10 V) to the specimen and observing the changes in the binding energies of various peaks can be used to learn about the electrical contact of a specimen (or parts of a specimen) with the specimen holder. Peaks in XPS spectrum that shift when the bias is applied are from conducting regions of the specimen. Other peaks from insulating regions may not shift nearly as much or at all and can be interpreted accordingly. This method can sometimes verify that the peaks being used for charge referencing (for example, Au 4f or C 1s) are behaving in the same manner as the peaks of interest from the specimen **(1,8,9)**. For nonuniform or composite (nonconducting) specimens, a variety of charge shifts may be observed upon biasing.

7.1.1.5 *Low Energy Ion Source*—Recent work indicates that portions of an insulator surface can be negatively charged, even when some areas exposed to X-rays are charged positively **(10)**. Such effects appear to be particularly important for focused X-ray beam systems, where the X-rays strike only a relatively small portion of the specimen. In these circumstances the use of a low-energy positive-ion source, in addition to an electron source, may help stabilize (and make more uniform) the surface potential of the specimen.

7.2 *Binding Energy Reference Methods:*

7.2.1 *Adventitious Carbon Referencing (1,2,8,11-15)*—Unless specimens are prepared for analysis under carefully controlled atmospheres, the surface, generally, is coated by adventitious contaminants. Once introduced into the spectrometer, further specimen contamination can occur by the adsorption of residual gases, especially in instruments with oil diffusion pumps. These contamination layers can be used for referencing purposes if it is assumed that they truly reflect the steady-state static charge exhibited by the specimen surface and that they contain an element with a peak of known binding energy. Carbon is most commonly detected in adventitious layers, and photoelectrons from the C 1s transition are those most often adopted as a reference.

7.2.1.1 A binding energy of 284.8 eV is often used for the C 1s level of this contamination and the difference between the measured position in the energy spectrum and the reference value, above, is the amount of surface potential shift caused by charging.

7.2.1.2 The main disadvantage of this method lies in the uncertainty of the reference values as reported in the literature **(2,12,13)** that ranges from 284.6 to 285.2 eV for the C 1s electrons. Therefore, it is recommended that if adventitious

³ The boldface numbers given in parentheses refer to a list of references at the end of the text.

carbon is to be used for referencing, the reference binding energy should be determined on the user's own spectrometer. Ideally, this measurement should be carried out on a substrate similar in its chemical and physical properties to the material to be analyzed and covered by only a thin, uniform contamination layer (that is, of the order of a monolayer).

7.2.1.3 Care must be taken where adventitious hydrocarbon can be chemically transformed, as, for example, by a strongly oxidizing specimen (13). With less than one monolayer coverage of adventitious carbon, the C 1s binding energy sometimes decreases (14). The carbon binding energy may also shift as a consequence of ion sputtering; evidence has been found for carbon of lower binding energy, possibly graphite or, more likely, carbon in domains approaching atomic dimensions (8). Despite the limitations and uncertainties associated with the use of adventitious carbon for static-charge referencing, it is the most convenient and commonly applied technique.

7.2.2 *Gold Decoration (2,3,11,16-19)*—Traditionally, “gold decoration” refers to the application of a uniform thin layer (0.5 to 0.7 nm) of elemental gold to the entire surface of an insulator in order to provide a metal calibrant on the sample surface. This layer is also connected to the spectrometer by mechanical contact with the sample holder so that both the spectrometer and the layer are at the same electrical potential. It is assumed that the contact between the deposited layer and the surface of the specimen is sufficient to establish a path that removes the specimen surface charge and positions the specimen binding energy position at a value that can be referenced to the gold binding energy. In practice, it has been found that for gold coverages, often less than one monolayer, there may be a reaction with the substrate. In addition to producing changes in the specimen, binding energies, such reactions may cause a chemical shift of the Au 4f peak (18,19), and result in a different binding energy than expected for the gold metal reference. The influence of such reactions with the gold calibrant should decrease as the gold overlayer thickness increases. However, shifts in the Au 4f peak can occur with thickness of the deposited material and with changes in its morphology. In addition, it must be remembered that thick gold coverages may not form continuous layers and differential charging between the gold “islands” and the specimen may occur. Because of the many sources of uncertainty, this method is no longer widely used for XPS measurements.

7.2.3 *Implantation with Inert Gases (20)*—Assumed binding energies of inert gases in solids have been used to measure the amount of charging in insulating specimens if the specimens are implanted with such a gas (20). However, such implantation may change the chemistry of the specimen and induce binding energy shifts in the sample. It has also been demonstrated that measured binding energies for an implant species can vary in different matrices because of varying relaxation effects (21).

7.2.4 *Internal Referencing*—Sometimes the specimen is of

such a nature that a portion of it has spectral lines of known binding energy that can be used as the charge reference (11). This method assumes the invariance of the binding energy of the chosen chemical group in different molecules. The measured peak energy will include the static charge of the specimen. A shift factor, calculated to correct the binding energy of the reference chemical group to the assumed value, can be applied to other measured peaks. If carbon is used, the technique is called internal carbon referencing.

7.3 *Bias Referencing (9)*—This method of charge referencing uses a small amount of a known external calibrant with an electron flood gate to reference an insulating surface. Typically, a small gold dot (1 to 3-mm diameter and 250 Å thick) is placed on the specimen surface by vacuum evaporation. XPS spectra of both the gold dot and a representative area on the specimen surface are obtained under the influence of a negative bias (approximately 10 V) that may be produced by electrons from a standard neutralizer. Resulting spectra can be referenced to gold by the application of a shift factor, calculated from the difference between the Au 4f_{7/2} peak under negative bias conditions and that same peak when the gold dot is in electrical contact with the spectrometer. In practice, Au 4f_{7/2} spectra are usually examined before and after obtaining data from the specimen in order to monitor system drift. It appears that this method brings about vacuum level alignment rather than Fermi level alignment and so may not be independent of the surface work function (9).

7.4 *Auger Parameter (22-24)*:

7.4.1 The Auger parameter is defined as the kinetic energy of the sharpest Auger peak in the spectrum minus the kinetic energy of the most intense photoelectron peak from the same element (22). (The energy of the ionizing photons must be specified before comparisons can be made between Auger parameter values.) The two measured transitions are equally affected by static charging of the specimen surface, hence, the calculation of the Auger parameter results in a value that is independent of charging for most spectrometers. Because the Auger parameter may change with chemical bonding, this charge-independent value can sometimes be used to assist in the identification of the chemical state of an element (22,23).

7.4.2 The modified Auger parameter is defined as the sum of the Auger parameter and the incident photon energy. (Or, alternately, as the sum of the kinetic energy of the sharpest Auger peak in the spectrum plus the binding energy of the most intense photoelectron peak from the same element.) The modified Auger parameter is independent of photon energy and is often used instead of the Auger parameter to assist in the identification of the chemical state of an element.

8. Keywords

8.1 charge control; charge referencing; charging; X-ray photoelectron spectroscopy

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